

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/621,090	NATSUKARI ET AL.	
Examiner	Art Unit	
Seung H. Lee	2876	

SEARCHED				
Class	Subclass	Date	Examiner	
235	462.09	^{\ 4/4/2005}	SHL	
235	462.10	4/4/2005	SHL	
235	462.22	4/4/2005	SHL	
235	462.23	4/4/2005	SHL	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
			1		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	4/4/2005	SHL	
K. Frech	4/4/2005	SHL	
NPL	4/4/2005	SHL	
PCT cites	4/4/2005	SHL	